

General Description

The RD3P100SNFRATL use advanced SGT MOSFET

technology to provide low RDS(ON), low gate charge,

fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness

and suitable.



General Features

 $V_{DS} = 100V I_{D} = 12 A$

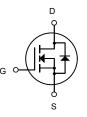
 $R_{DS(ON)}$ < 120m Ω @ V_{GS} =10V

Applications

Consumer electronic power supply

Motor control

Synchronous-rectification



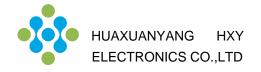
N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
RD3P100SNFRATL	TO252-2L(TO-252(DPAK))	HXY MOSFET	2500

Absolute Maximum Ratings at T_i=25°C unless otherwise noted

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	100	V
VGS	Gate source voltage	±20	V
ID	Continuous drain current ¹⁾	12	А
ID, pulse	Pulsed drain current ²⁾	24	А
P _D	Power dissipation ³⁾	17	W
EAS	Single pulsed avalanche energy ⁴⁾	1.2	mJ
Tstg,Tj	Operation and storage temperature	-55 to 150	℃
RθJC	Thermal resistance, junction-case	6.6	°C/W
RθJA	Thermal resistance, junction-ambient ⁵⁾	62	°C/W



Electrical Characteristics T_C=25 °C unless otherwise specified

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units		
Off Chara	Off Characteristic							
V _{(BR)DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250 \mu A$	100	110	-	V		
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 100V, V _{GS} = 0V	-	-	1	μA		
Igss	Gate to Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA		
On Charac	cteristics note3							
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.0	1.8	3.0	V		
R _{DS(on)}	Static Drain-Source On-Resistance note2	V _{GS} = 10V, I _D = 3A	-	95	120	mΩ		
Dynamic (Characteristics note4		l .	ı	l .			
Ciss	Input Capacitance	V _{DS} = 50V, V _{GS} = 0V, f = 1.0MHz	-	196	-	pF		
Coss	Output Capacitance		-	25.9	-	pF		
Crss	Reverse Transfer Capacitance		-	21.4	-	pF		
Qg	Total Gate Charge	V _{DS} = 50V, I _D = 3A,	-	4.3	-	nC		
Qgs	Gate-Source Charge		-	3.5	-	nC		
Q _{gd}	Gate-Drain("Miller") Charge	V _{GS} = 10V	-	3.1	-	nC		
Switching	Characteristics note4							
t _{d(on)}	Turn-On Delay Time	., 50,/, 04	-	14.7	-	ns		
tr	Turn-On Rise Time	$V_{DD} = 50V$, $I_{DS} = 3A$	-	3.5	-	ns		
t _{d(off)}	Turn-Off Delay Time	$R_G = 2\Omega$, $V_{GEN} = 10V$	-	20.9	-	ns		
t _f	Turn-Off Fall Time		-	2.7	-	ns		
Drain-Sou	rce Diode Characteristics and Maximum Rati	ngs						
ls	Maximum Continuous Drain to Source Diode Forward Current note2		-	-	12	Α		
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	12	Α		
V _{SD}	Drain to Source Diode Forward Voltage note3	V _{GS} = 0V, I _S =3A	-	-	1.3	V		
t _{rr}	Body Diode Reverse Recovery Time	\/ - 0\/ I - 2A	-	32.1	-	ns		
Q _{rr}	Body Diode Reverse Recovery Time Charge	V _{GS} = 0V, I _F = 3A, di/dt =100A/µs	-	39.4	-	nC		
I _{rrm}	Peak Reverse Recovery Current	- ui/ut – τυυΑ/μs	-	2.1	-	Α		

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤2%.
- 4. Guaranteed by design, not subject to production
- 5. V_{DD} =50 V, R_G =50 Ω , L=0.3 mH, starting T_j =25 °C

Typical Performance Characteristics

Figure1: Output Characteristics

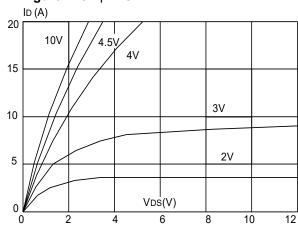


Figure 2: Typical Transfer Characteristics

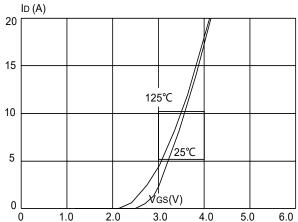


Figure 3:On-resistance vs. Drain Current

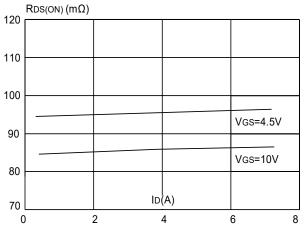


Figure 4: Body Diode Characteristics

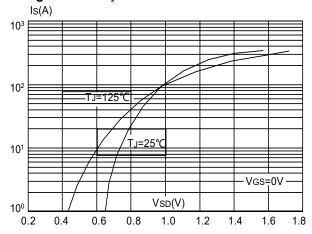
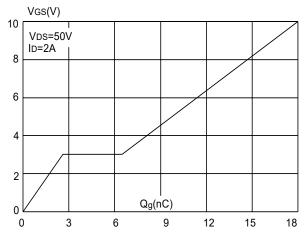
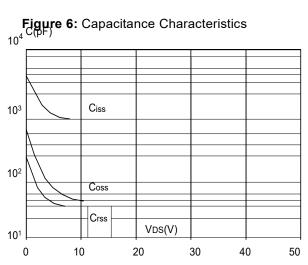


Figure 5: Gate Charge Characteristics





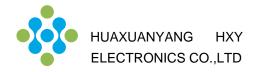


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

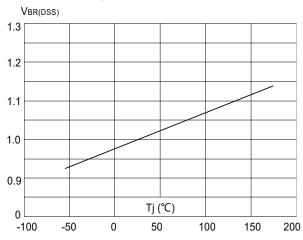


Figure 9: Maximum Safe Operating Area

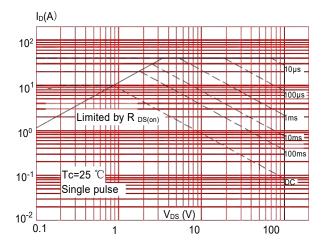


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

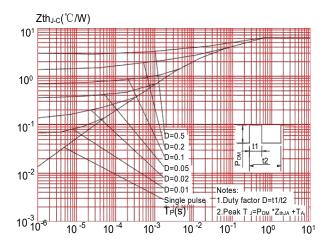


Figure 8: Normalized on Resistance vs. Junction Temperature

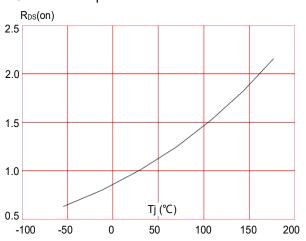
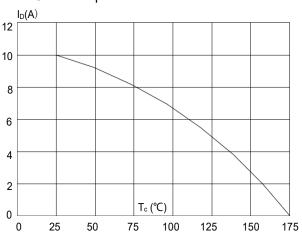
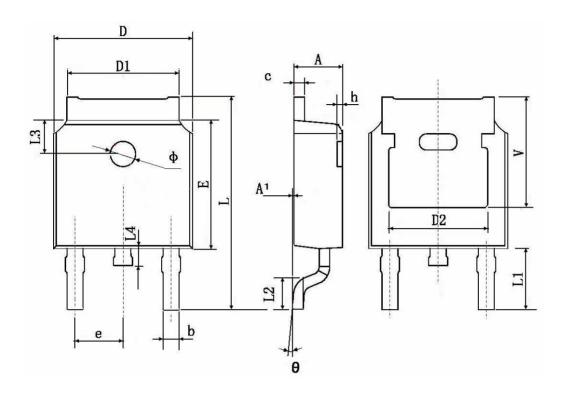


Figure 10: Maximum Continuous Drain Current vs. Case Temperature





TO-252-2L(DPAK) Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	TYP.	0.211 TYP.		

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